Appl. No. 10/179,314

Amendment/Response

Reply to non-Final Office action of 10 June 2003

## Listing of Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

- 1. (Currently amended) An X-ray microscope which includes a device for generating X-rays, a lens for forming an image of an object, and an X-ray detector for detecting an image of the object, the device for generating X-rays provided with:
  - means for producing a fluid jet having a curvilinear cross-section,
  - means for forming a focused radiation beam whose focus is situated on the fluid jet,

said focused radiation beam comprising a beam of electrically charged particles,

wherein the cross-section of the fluid jet in the direction of the focused beam is smaller than that in the direction transversely thereof.

- 2. (Previously presented) An X-ray microscope as claimed in Claim 1, wherein the beam of electrically charged particles comprises an electron beam.
- (Cancelled)
- 4. (Previously presented) An X-ray microscope as claimed in Claim 1, wherein the fluid jet consists essentially of liquid oxygen or nitrogen.
- 5. (Previously presented) An X-ray microscope as claimed in Claim 1, wherein the means for producing a focused beam of

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electrically charged particles comprises an electron gun for a cathode ray tube, the X-ray microscope including a condenser lens disposed between the fluid jet and an object to be imaged by means of the X-ray microscope.

- 6. (Currently amended) An electron microscope comprising means for producing a focused electron beam, a device for generating X-rays, a lens for forming an image of an object, and a detector for detecting the image of the object, said device for generating X-rays including:
  - means for producing a fluid jet having a curvilinear cross-section, and
  - means for directing the focus of the electron beam onto the fluid jet,

wherein the cross-section of the fluid jet in the direction of the focused beam is smaller than that in the direction transversely thereof.

- 7. (Previously presented) An electron microscope as claimed in Claim 6 and including an X-ray microscope, said device for generating X-rays acting as the X-ray source for the X-ray microscope.
- 8. (Previously presented) An electron microscope as claimed in Claim 6, the electron microscope being a scanning electron microscope.